H.T No: **R22** Course Code: B455303



CMR COLLEGE OF ENGINEERING & TECHNOLOGY

(UGC AUTONOMOUS)
M.Tech II Semester Regular Examinations September-2023

	(Embedded Systems)	
	Date: 04.09.2023 FN Time: 3 hours	Max.Marks: 60
	(Note: Assume suitable data if necessary) PART-A Answer all TEN questions (Compulsory)	
	Each question carries ONE mark.	10x1=10M
1.	Write Embedded system hardware and software.	1 M
2.	Write about ARM -APSR instructions.	1 N
3.	What is Thumb state?	1 M
4.	Write a short note on long multiplication.	1 M
5.	Distinguish between Cross Compiler and Cross Assembler.	1 M
6.	Explain the segment memory management scheme.	1 M
7.	What are the instruction dependencies in ARM? Explain each briefly.	1 M
8.	Write a short note on UAL.	1 M
9.	Write a short note on Cortex –M4 FPU.	1 M
10.	Explain FMUL and FMULP instructions.	1 M
	PART-B	
	Answer the following. Each question carries TEN Marks.	5x10=50M
11.A	A). Discuss in detail the hardware fundamentals of the actual ARM processor.	10M
	OR	
11. I	B). Explain the 3-stage pipeline ARM organization.	10N
12. /	A). Explain the Interrupt service routines (ISRs). What are the advantages of ISR?	10M
	OR	
12. E	B). Explain ARM design methodology requirements analysis.	10M
13. A	A). Briefly explain the data processing instructions for ARM processor	10M
	OR	1011
13. E	B). Describe in detail the following Thumb instructions: i) Register usage instructions ii) Single-register load-store instructions	ctions and 10M
14. <i>A</i>	A). What is context switching? With figure and assembly code explain two stage context switch.	ges of the 10M
	OR	
14. B	3). Comparison of the instruction set in ARM Cortex-M Processors.	10M
15. A	A). Mention useful techniques for optimizing ARM assembly, and briefly explain the OR	em. 10M
15. B		10M
	A A A A A A A A A A A A A A A A A A A	10101

12. B). Examine whether the discrete data system given below is $X(k+1) = \begin{bmatrix} 0 & 1 \\ -2 & -2 \end{bmatrix} X(k) + \begin{bmatrix} 1 \\ -1 \end{bmatrix} u(k); y(k) = \begin{bmatrix} 1 & 0 \end{bmatrix} X(k)$ (i) State controllable (ii) Output controllable (iii) Observable

13. A). Using bilinear transformation, explain the design procedure of lag and lead 10M Compensators.

OR

Using Jury stability criterion, find if all the poles of the following transfer function lie 10M inside the unit circle on the z-plane.

$$G(z) = \frac{3z^4 + 2z^3 - z^2 + 4z + 5}{z^4 + 0.5z^3 - 0.2z^2 + z + 0.4}$$

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(P.T.O..)

14. A). Consider the system $X(k+1) = \begin{bmatrix} 0 & 1 \\ -0.16 & -1 \end{bmatrix} X(k) + \begin{bmatrix} 0 \\ 1 \end{bmatrix} u(k)$; 10M

Design a current observer for the system. It is desired that the response to the initial observer error be deadbeat.

OR

14. B). Explain the design procedure of digital PID controllers.

10M

15. A). Illustrate any two methods of pole-placement for design of digital controller.

OR

15. B). Discuss the necessary conditions for design of state feedback controller through pole 10M placement.



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1. 2. 3. 4. 5. 6. 7. 8. 9.	(Note: Assume suitable data if necessary) PART-A Answer all TEN questions (Compulsory)	1 M 1 M 1 M 1 M
2. 3. 4. 5. 6. 7. 8. 9.	(Note: Assume suitable data if necessary) PART-A Answer all TEN questions (Compulsory) Each question carries ONE mark. Define the role of testing and role of diagnosis in VLSI. Define the terms defect and fault. What is the application of logic level modeling and simulation? What are the signal values used at circuit level modeling and simulation? What is 0-controllability(C0)? Define the length of a sequential path. Define degree of parallelism.	10x1=10M 1 M 1 M 1 M 1 M 1 M
2. 3. 4. 5. 6. 7. 8. 9.	Define the role of testing and role of diagnosis in VLSI. Define the terms defect and fault. What is the application of logic level modeling and simulation? What are the signal values used at circuit level modeling and simulation? What is 0-controllability(C0)? Define the length of a sequential path. Define degree of parallelism.	1 M 1 M 1 M 1 M
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3. 4. 5. 6. 7. 8. 9.	What is the application of logic level modeling and simulation? What are the signal values used at circuit level modeling and simulation? What is 0-controllability(C0)? Define the length of a sequential path. Define degree of parallelism.	1 M 1 M 1 M
4. 5. 6. 7. 8. 9.	What are the signal values used at circuit level modeling and simulation? What is 0-controllability(C0)? Define the length of a sequential path. Define degree of parallelism.	1 M 1 M
5. 6. 7. 8. 9.	What is 0-controllability(C0)? Define the length of a sequential path. Define degree of parallelism.	1 M
6. 7. 8. 9.	Define the length of a sequential path. Define degree of parallelism.	1 M
7. 8. 9. 10.	Define degree of parallelism.	
8. 9. 10.	그 나는 아이들이 아이들 때문에 가장하는데 하는데 아이들이 되었다. 그 그는 그를 가는 것이다. 그는 그를 가는 것이 없는 것이 없었다.	1 M
9. 10.	Define fault coverage	1 M
10.	Beilie ladit coverage.	1 M
	List boundary scan registers.	1 M
I	Define noninvasive mode of boundary scan.	
I	PART-B	1 M
	Answer the following. Each question carries TEN Marks.	5x10=50M
11.A)). How do you address bridging and delay faults?	103
	OR	10M
11. B		
11. D). Explain Single stuck – Fault model with an example.	10M
12. A	The deductive fault simulation procedures.	10M
12 D	OR	
12. B)	 Explain what action an event-driven true-value simulator will take when it evaluated zero-delay gate. 	ates a 10M
13. A). i) Explain generic scan-based designs.	5M
	ii) Explain the level sensitive scan design rules	5M
	OR	
13. B)). i) What is Transition-count compression? Elaborate.	5M
	ii) Write a brief note on BILBO architecture.	5M
14. A)		
14.71	Section of the Bis i Michigan	10M
14. B)	OR	
14. D)). Discuss on A concurrent BIST Architecture with neat sketch.	10M
15. A)). Draw and explain TAP controller state diagram and timing diagram OR	10M
15. B)		
	i) Explain control-and -observe scan cell method.	5M



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M.Tech II Semester Regular Examinations September-2023

	Course Name: HARDWARE & SOFTWARE CO-DESIGN				
	Date: 11.09.2023 FN	(Embedded Systems) Time: 3 hours	M M 1 (0		
	2400 110012020 111	(Note: Assume suitable data if necessary) PART-A	Max.Marks: 60		
		Answer all TEN questions (Compulsory) Each question carries ONE mark.	10x1=10M		
1.	List the types of Architect	tures.	1 M		
2.	Explain the need of co-sy	nthesis.	1 M		
3.	Draw the Architecture of VLIW.		1 M		
4.	Explain data flow graph.	1 M			
5.	Define compiler.		1 M		
6.	Define ASIC.		1 M		
7.	What is Emulation?		1 M		
8.	Draw the Architecture of	FPGA based emulation.	1 M		
9.	Define co-design.		1 M		
10.	Define scheduling.		1 M		
			1 141		
		PART-B			
	Answer the following. Each	ch question carries TEN Marks.	5x10=50M		
11.4	A). Explain Data path Arc	hitecture and its working principle.	10M		
		OR	TOW		
11.	B). Draw the flow graph o	f Cosyma and explain the working of each block.	10M		
12.	A). Draw and explain the l	block diagram of prototyping and emulation techniques.	10M		
		OR	TOW		
12.1	B). Explain Aptix prototyr	ping systems with neat diagrams	10M		
	1 1 1 1	g cycles with new diagrams	TOW		
13. /	A). Draw the architecture of	of CISC and explain.	10M		
		OR			
13. I	3). Explain the architectur	e of parallel processor.	10M		
14. A	A). Explain system special	ization techniques.	10M		
		OR			
14. E	B). Explain design and co-	design computation models.	10M		
15 /) Eymlein Tenest Auslite				
15. A	i). Explain Target Archite	ctures and application system classes.	10M		
15 D	Draw the flament	OR			
13. E	o). Draw the flow graph of	f Cosyma and explain the working of each block.	10M		